

Notice of References Cited	Application/Control No. 10/775,146	Applicant(s)/Patent Under Reexamination TAKIZAWA, TERUO	
	Examiner Jennifer M. Dolan	Art Unit 2813	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-2002/0168802	11-2002	Hsu et al.	438/149
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.